

CLAIM AMENDMENTS

1. (Currently Amended) A method of evaluating a piezoelectric field comprising ~~the steps of:~~

measuring a first absorption spectrum of a sample by irradiating ~~infrared light to said~~ the sample with infrared light at a first angle;

measuring a second absorption spectrum of ~~said~~ the sample by irradiating the ~~infrared light to said~~ sample with the infrared light at a second angle, different from the first angle;

specifying a peak position of an absorption band having incident-angle dependent intensity based on the first absorption spectrum and the second absorption spectrum; and

obtaining the piezoelectric field strength ~~based on an equation representing~~ using a relationship between the piezoelectric field and ~~an~~ electron energy level corresponding to the peak position of the absorption band.

2. (Currently Amended) The method according to claim 1, wherein the piezoelectric field is an electric field induced by a lattice-mismatch strain in a semiconductor heterojunction of ~~said~~ the sample.

3. (Currently Amended) The method according to claim 1, wherein ~~said step of~~ measuring the first absorption spectrum includes:

measuring, in advance, a reference spectrum by changing wavelength of the infrared light within a predetermined range;

irradiating the ~~infrared light to said~~ sample by with the infrared light and changing the wavelength of the infrared light within the predetermined range; and

calculating the first absorption spectrum based on the infrared light which is transmitted through ~~said~~ the sample.

4. (Currently Amended) The method according to claim 1, wherein ~~said step of~~ measuring the second absorption spectrum includes irradiating the ~~infrared light~~ sample with the infrared light at the second angle by rotating a turntable on which ~~said~~ the sample is placed.

5. (Currently Amended) The method according to claim 4, wherein ~~said step of~~ measuring the second absorption spectrum includes:

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detecting a deviation of an optical axis of the infrared light which is ~~irradiated to said~~
irradiates the sample and is transmitted through ~~said the~~ sample;
correcting the deviation of the optical axis; and
calculating the second absorption spectrum based on the infrared light which is
transmitted through ~~said the~~ sample.

6. A method of evaluating a piezoelectric field comprising ~~the steps of:~~
measuring a first absorption spectrum of a sample by irradiating ~~infrared light to said~~
the sample with infrared light;
measuring a second absorption spectrum of ~~said the~~ sample by irradiating ~~infrared~~
light to said the sample, while placed on a turntable, said with infrared light, and vibrating the
turntable being vibrated with a predetermined angular frequency;
specifying a peak position of an absorption band having incident-angle dependent
intensity based on the first absorption spectrum and the second absorption spectrum; and
obtaining the piezoelectric field strength ~~based on an equation representing~~ using a
relationship between the piezoelectric field and ~~an~~ electron energy level corresponding to the
peak position.